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patents [Advance](#)**Patents**Patents **1 - 10** on **environmental value results calculation and manufacturing**. (0.09 seconds)› **List view**[Cover view](#)› **Sort by relevance**[Sort by date \(new first\)](#)[Sort by date \(old first\)](#)› **Any status**[Issued patents](#)[Applications](#)[Lot start agent that calculates virtual WIP time in a multi-product and ...](#)

US Pat. 6564113 - Filed Jun 15, 2001 - Advanced Micro Devices, Inc.

The **value** of W^A provides the specific weight to be applied to Step N, the **value**of W^A being ... Table 1.2 illustrates the **calculation** of the sum of weighted ...[System for monitoring and analyzing **manufacturing** processes using ...](#)

US Pat. 5719796 - Filed Dec 4, 1995 - Advanced Micro Devices, Inc.

A large number of 15 highly variable factors influence process **results**. ... whatis truly known is fied **value** of a parameter is fitted to produce a ...[Method for monitoring and analyzing **manufacturing** processes using ...](#)

US Pat. 5966312 - Filed Nov 7, 1997 - Advanced Micro Devices, Inc.

Process **results** are typically difficult to measure with accuracy. ... In conventional **manufacturing** process calibration, a specified **value** of a parameter is ...[Method and apparatus for performing run-to-run control in a batch ...](#)

US Pat. 6607926 - Filed Aug 10, 1999 - Advanced Micro Devices, Inc.

The **value** of the error corresponding to a control input signal is used to updatethat control input signal for a subsequent **manufacturing** process step. ...[\[APPLICATION\] Methods and systems for controlling evaporative drying processes using ...](#)

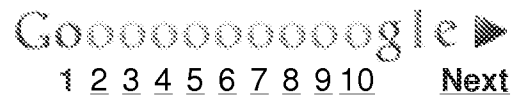
US Pat. 10864172 - Filed Jun 9, 2004

3 illustrates a control parameter **calculation** routine for calculating a control parameter **value** that **results** in a calculated **environmental** equivalency **value** ...[Methods and apparatus for the testing, monitoring and improvement of ...](#)

US Pat. 5617321 - Filed Dec 22, 1994 - Computer Sciences Corporation

The complexity, H, of a **manufacturing** system is a measure of that system's ... h) with a selection dependent on the **results** of the **calculation** at step j), ...[Environmental parameter measurement device and method for laser interferometry](#)

US Pat. 5920392 - Filed Dec 22, 1997 - Excel Precision, Inc.



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